

Wafer Fab Process Transfer for HI-8382/8383 & HI-8588/8588-10 Series of ARINC 429 Products

Product Change Notice

PCN0811 (v1.0) December 02, 2008

Overview

The purpose of this notice is to announce the completed transfer of the Holt devices manufactured using the 100mm 4.0um CMOS Wafer Process at Dalsa Semiconductor in Quebec, Canada to Dalsa's 150mm 4.0um CMOS Wafer Process within the same fab.

Description

Holt Integrated Circuits has transferred the following ARINC 429 products to the already Holt qualified 150mm 4.0 micron CMOS wafer manufacturing process.

The 4.0um CMOS 2 layer metal semiconductor process is fully qualified at DALSA, Quebec. (See Qualification Data in Table 2) Dalsa, Quebec has been a qualified supplier of Holt wafers for over 10 years and is ISO/ TS 16949 certified.

There is no change to Fit, Form, Function, Quality or Reliability of these devices. Product manufactured using die fabricated on the qualified 150mm 4.0 micron CMOS Wafer line at Dalsa Semiconductor is completely compatible with existing product from a functional, parametric, quality, and reliability performance.

The design and electrical specification are per the data sheet. All full characterization over the datasheet specified operating temperature and voltage range has been performed to confirm the device is fully functional and meets all electrical specifications.

Reason

Holt Integrated Circuits will be able to ensure the continuity of supply of the following products to customers once Dalsa Semiconductor closes their 100mm 4.0 micron CMOS wafer process line.

Products Affected

Table 1 summarizes the products affected by this PCN. All parts listed are affected by this change.

Table 1: Products	Affected				
HI-8382C	HI-8382S	HI-8382J	HI-8588PDI	HI-8588PDI-10	HI-8588CRI
HI-8382CT	HI-8382ST	HI-8382JF	HI-8588PDIF	HI-8588PDIF-10	HI-8588CRT
HI-8382CM	HI-8382SM	HI-8382JT	HI-8588PDT	HI-8588PDT-10	HI-8588CRM
HI-8382CM-01	HI-8382SM-01	HI-8382JTF	HI-8588PDTF	HI-8588PDTF-10	HI-8588CRI-10
HI-8382CM-03	HI-8382SM-03	HI-8382U	HI-8588PDM	HI-8588PDM-10	HI-8588CRT-10
HI-8382CM-21		HI-8382UT	HI-8588PDMF	HI-8588PDMF-10	HI-8588CRM-10
HI-8383C	HI-8383S	HI-8383J	HI-8588PSI	HI-8588PSI-10	
HI-8383CT	HI-8383ST	HI-8383JF	HI-8588PSIF	HI-8588PSIF-10	
HI-8383CM	HI-8383SM	HI-8383JT	HI-8588PST	HI-8588PST-10	
HI-8383CM-01	HI-8383SM-01	HI-8383JTF	HI-8588PSTF	HI-8588PSTF-10	
HI-8383U	HI-8383UT		HI-8588PSM	HI-8588PSM-10	

Traceability

There will be no changes to product ordering codes or marking. Holt maintains traceability of product to the wafer level through the lot number marked on the package. Beginning March 01, 2009 shipments can be built using wafers from either Wafer Fab Process line until inventory of the 100mm line is depleted.

HI-8588PSMF

HI-8588PSMF-10



Qualification Data

Table 2:

Stress/Test	Test Conditions	Industry Standard	Accept Criteria Fail/SS	Device
High Temperature Operating Life	Static Operating Condition, Tj ≥+125 °C, Vcc ≥ Vccmax, 168, 500, & 1000 Hrs	JESD22-A108	0/45	HI-8382CM HI-8588PSI
Latch-up	Ta = +25°C	JESD78	0/6	HI-8588PDI
Electrostatic Discharge Human Body Model (ESD_HBM)	Ta = +25°C	JESD22-A114	Classification	

Successful qualification of this selected product qualifies all other listed products in this device type.

Response

Note: In accordance with JESD46-C, this change is deemed accepted by the customer if no acknowledgement is received within 30 days from this notice.

No response is required. For additional information or questions, please contact:

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Additional Documentation

Below is a list of documents that are associated with this notice:

- O QR-8005 Rev. 1.0 HI8590 Rev. K 150mm Wafer Conversion
- O QR-8006 Rev. 1.0 HI8590 Rev. L 150mm Wafer Conversion
- O QR-8007 Rev. 1.0 HI8382 Rev. N 150mm Wafer Conversion

Revision History

The following table shows the revision history for this document.

Date	Version	Revision Description
12/02/08	1.0	Initial Release